

ming the compliance voltage of the tester's parametric measurement units (PMU). Since R_s and the forced current are known, the actual output level can easily be calculated with sufficient accuracy. It is:

$$V_{out} = V_{measure} - V_{drop} = V_{measure} - R_s I_f \quad (16)$$

For best results, 0.1% resistors are recommended for R_s .

Summary

In the HP 82000 IC Evaluation System, the resistive divider method offers advantages in operating speed and

measurement accuracy. The method has its restrictions and does not ensure testability of every DUT.

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